

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) PRM-0052		Application Number 10/550,643		
				Applicant(s) Kunihiko Iwamoto et al.				
				Filing Date 09/23/2005		Group Art Unit 2826		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
U.S. PATENT APPLICATION PUBLICATIONS								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO	
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
/ER/		Copy of the International Preliminary Report on Patentability for related International Application No. PCT/JP2004/004060 mailed March 2, 2006 with English translation.						
EXAMINER /Eduardo Rodela/				DATE CONSIDERED 06/25/2007				
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INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. PRM-0052		APPLICATION NO. 10/250643	
				APPLICANT(S) Kunihiko Iwamoto et al.			
				FILING DATE 9/23/05		GROUP ART UNIT 2826	
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/ER/		JP 59-011663	01/21/1984	Japan (w/English abstract)			
/ER/		JP 2002-299607	10/11/2002	Japan (w/English abstract)			
/ER/		JP 2003-008011	01/10/2003	Japan (w/English abstract)			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
/ER/		International Search Report for Application No. PCT/JP2004/004060 mailed 07/13/2004					
/ER/		Sanghun Jeon, et al. "Electrical characteristics of ZrOxNy prepared by NH3, annealing of ZrO2" Applied Physics Letters, Volume 79, Number 2, July 9, 2001, Pgs. 245-247.					
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

/ER/		Hyung-Seok Jung et al. "Improved Current Performance of CMOSFETs with Nitrogen Incorporated HfO ₂ -Al ₂ O ₃ Laminate Gate Dielectric", Electron Devices Meeting, 2002. IEDM' 02. Digest. International, 2002, 12, pages 853-856.
/ER/		T. Nishimura et al. "Effects of Nitrogen Incorporation into HfAlO _x Films on Gate Leakage Current - From XPS Study of Hf Bonding States", Extended Abstracts of International Workshop On Gate Insulator 2003, 11, pages 180-185.

EXAMINER <div style="text-align: center;">/Eduardo Rodela/</div>	DATE CONSIDERED <div style="text-align: center;">06/25/2007</div>
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